

### Automated Multi-Channel RF-Biased Burn-In Test System Summary

The Automated Multi-Channel RF-Biased Burn-In Test System is a turnkey system that incorporates all of the capability needed for accelerated-aging and parametric testing of RF semiconductor devices. This architecture has been designed to minimize cost-per-channel; ideal for production burn-in testing. Yet, its powerful software elegantly supports data acquisition, storage, and presentation. Accel-RF's platform solution is the only integrated instrument that can demonstrate compliance with aerospace, government, and commercial RF semiconductor life-test and burn-in standards (GaAs, SiGe, GaN, SiC, InP and RFICs). Accel-RF's Burn-in Test System is used by a majority of the global community of wide band-gap (WBG) semiconductor manufacturers and component integrators.

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#### Highlights

**Up to 16 Channels per Tray**

**Up to 128 Channels per Platform**

**Modular, Low-Cost per Channel Configuration**

#### Standard Frequency Ranges:

- 1 to 4 GHz, 8 to 12 GHz, 13 to 17 GHz, Millimeter bands (custom)

#### RF Drive Levels

- Variable from -5 to 15dBm
- Support for Optional SSPA
- Up to 100 Watts Input Power Available

#### Power Supplies

- Drain (0.5 to 100V; 50W/CH)
- Gate (+/-10V 4-Quadrant)
- Individual Gate Control for Setting Drain Current per Device



Heater Control Unit		
Useable Range Settability, Accuracy Stability or Drift	+50°C to 200°C +/-5°C <5°C in 200 hrs	No load -> maximum baseplate temperature not to exceed +205°C 4 DUTS per heater, +/-3°C across 4 DUT positions Assumes constant DUT load power dissipation and between 20% and 90% duty factor operation
Setting Time Overshoot	<60 minutes <10°C	Assumes constant DUT load power dissipation
DC Bias Control		
<b>Bias1 Voltage</b>  Operational Range Settability, Resolution Settability, Accuracy Measurement Accuracy Source Drift Measurement Drift	0.5 to +100V 0.02% FSR 1% target, or 0.1% FSR 0.05% FSR <0.05% FSR in 100 hrs <0.05% FSR in 100 hrs	Note: A common Bias1 supply services up to 8 DUTs and Maximum Power on Bias1 is 400W (V*I)-> Total Maximum for 8 DUTs  ->20mV Whichever is greater (1% limited by software) ->50mV ->50mV ->50mV
<b>Bias1 Current</b>  Optional Range DUT Drain Current Measurements: Measurement Accuracy Measurement Drift	0 to +4A  1% FSR <0.1% FSR in 100 hrs	Note: Total for 8 DUTs and 50W maxDC power per channel (Maximum 200W maxDC power per group of 4 DUTs on Heater Block)  Note: FSR = +0.5A per device ->5mA ->0.5mA
<b>Bias2 Voltage</b>  Operational Range DUT Gate Voltage: Settability, Resolution Measurement Accuracy Source Drift Measurement Drift	-10 to +10V  Continuous 0.1% FSR <0.1% FSR in 100 hrs <0.05% FSR in 100 hrs	Note: A common Bias2 supply services up to 8 DUTs, Maximum Power on Bias2 is 10W (V*I)->Total Maximum for 8 DUTs and Individual gate control exists per device in the burn-in tray  Note: FSR = 20V per device Adjustable via pot on burn-in board ->20mV ->20mV (5mV typ.) ->10mV (5mV typ.)
<b>Bias2 Current</b>  Operational Range DUT Gate Current: Measurement Accuracy Measurement Drift	-500 to +500mA  0.5% FSR <0.1% FSR in 100 hrs	Note: Individual gate currents are limited by burn-in tray on-board op-amp limitations, not the global Bias2 supply Note: Gate current FSR = 50mA per device ->250µA ->50µA (20µA typ.)
RF Control		
DUT Input Power Level (for max setting)  DUT Output Power Level  Dynamic Range Frequency Range Settability, Resolution  Settability, Accuracy Measurement Accuracy Stability or Drift	>+15 dBm  <=+40 dBm (+50dBm option)  20dB 1-18 GHz, Millimeter-wave bands available 0.5 dB  0.5 dB 0.5 dB 0.5 dB in 200 hrs	Over F(low) to F(high), degradation of -1dB at band edges is acceptable At test device output (ie FET or HEMT or MMIC) Note: Output matching network or output 50-ohm circuit must be designed to handle device maximum output capability DUT input power adjustment level is a minimum of 20 dB (Band Specific- consult Accel-RF for bandwidth per drawer) As measured with better than 14dB return-loss load (~50-ohm input) via integrated detector diode As calibrated with better than 17dB return-loss load (~50-ohm input) As measured with better than 14dB return-loss load (~50-ohm input) Assumes continuous update operational mode into constant load
SSPA		
	Per Customer Specifics	Ability to upgrade with SSPA is integrated into each drawer (Requires external power supply) Liquid-cooled option required with SSPA integration